

**Notic of References Cited**Application/Control No.  
10/073,506Applicant(s)/Patent Under-  
Reexamination  
FALSTER ET AL.Examiner  
Matthew A. AndersonArt Unit  
1765

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6045610	04-2000	Park et al.	117/13
	B	US-5935320	08-1999	Graef et al.	117/2
	C	US-4548654	10-1985	Tobin et al.	148/1.5
*	D	US-6287380 B1	09-2001	Falster et al.	117/13
	E	US-6334896 B1	01-2002	Iida et al.	117/20
	F	US-6261361 B1	07-2001	Iida et al.	117/19
	G	US-6228164 B1	05-2001	Ammon et al.	117/19
	H	US-6139625	10-2000	Tamatsuka et al.	117/19
	I	US-6191009 B1	02-2001	Tamatsuka et al.	438/471
	J	US-6206961 B1	03-2001	Takeno et al.	117/20
	K	US-5385115	01-1995	Tomioka et al.	117/2
	L	US-5788763	08-1998	Hayashi et al.	117/2
	M	US-6129787	10-2000	Adachi et al.	117/89

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wolf et al., Silicon Processsing for the VLSI Era, Vol 1.: Process Technology, Chapter 2, Lattice Press, Sunset Beach, CA, USA, pp. 36-72, 1986.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6413310 B1	07-2002	Tamatsuhka et al.	117/3
	B	US-6409827 B2	06-2002	Falster et al.	117/15
	C	US-5403406	04-1995	Falster et al.	148/33.2
	D	US-5994761	11-1999	Falster et al.	257/611
	E	US-6245311 B1	06-2001	Kobayashi et al.	423/348
	F	US-6204188 B1	03-2001	Abe et al.	438/706
	G	US-6238990 B1	05-2001	Aga et al.	438/308
	H	US-5919302	07-1999	Falster et al.	117/3
	I	US-6236104 B1	05-2001	Falster	257/618
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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